

CNX82A.W, CNX83A.W, SL5582.W & SL5583.W

DESCRIPTION

The CNX82A.W, CNX83A.W, SL5582.W AND SL5583.W, consist of a gallium arsenide infrared emitting diode driving a silicon phototransistor in a 6-pin dual in-line package.

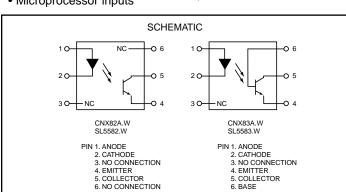
6

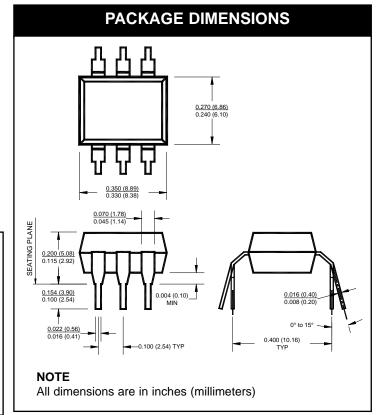
FEATURES

- Input/Output pin distance 10.16 mm
- UL recognized (File # E90700)

APPLICATIONS

- Power supply regulators
- Digital logic inputs
- Microprocessor inputs





Parameter	Symbol	Value	Units	
TOTAL DEVICE	_	55. 450	20	
Storage Temperature	T _{STG}	-55 to +150	°C	
Operating Temperature	T _{OPR}	-55 to +100	°C	
Lead Solder Temperature	T _{SOL}	260 for 10 sec	°C	
Junction Temperature	TJ	125	°C	
Total Device Power Dissipation @ T _A = 25°C	P _D	250	mW	
EMITTER	,	400	A	
DC/Average Forward Input Current	l _F	100	mA	
Reverse Input Voltage	V _R	5.0	V	
Forward Current - Peak (1µs pulse, 300pps)	I _F (pk)	3.0	Α	
LED Power Dissipation @ T _A = 25°C	Ъ	140	mW	
Derate above 25°C	P_{D}	1.33	mW/°C	
DETECTOR	V	50	V	
Collector-Emitter Voltage	V _{CEO}	50	V	
Collector-Base Voltage (CNX83A)	V _{CBO}	70	V	
Emitter-Collector Voltage	V _{ECO}	7	V	
Continuous Collector Current	I _C	100	mA	
Detector Power Dissipation @ T _A = 25°C	Ь	150	mW	
Derate above 25°C	P _D	2.0	mW/°C	



CNX82A.W, CNX83A.W, SL5582.W & SL5583.W

ELECTRICAL CHARACTERISTICS (T_A = 25°C Unless otherwise specified.)

INDIVIDUAL COMPONENT CHARACTERISTICS							
Parameter	Test Conditions	Symbol	Device	Min	Typ**	Max	Unit
EMITTER	() 40 ()		A1.1		4.0	4.50	V
Input Forward Voltage	$(I_F = 10 \text{ mA})$	V _F	ALL		1.2	1.50	V
Reverse Leakage Current	$(V_R = 5.0 V)$	I _R	ALL		0.001	10	μA
DETECTOR	(1 40 1 0)	D)/	A. I.	50	100		V
Collector-Emitter Breakdown Voltage	$(I_C = 1.0 \text{ mA}, I_F = 0)$	BV _{CEO}	ALL				
Collector-Base Breakdown Voltage	$(I_C = 100 \mu A, I_F = 0)$	BV _{CBO}	CNX83A.W	70	120		V
			SL5583.W	70			
Emitter-Collector Breakdown Voltage	$(I_E = 100 \mu A, I_F = 0)$	BV _{ECO}	ALL	7	10		V
	$(V_{CE} = 10 \text{ V}, I_F = 0)$	I _{CEO}	ALL		0.001	0.050	μΑ
	$(V_{CE} = 10 \text{ V}, I_F = 0)$ $(T_A = 70^{\circ}\text{C})$		CNX82A.W		0.5	10	
			CNX83A.W				
Collector-Emitter Dark Current			SL5582.W			0.5	
			SL5583.W			0.5	
	$(V_{CE} = 10 \text{ V}, I_F = 0)$		SL5582.W			50	
	$(T_A = 100^{\circ}C)$		SL5583.W			50	
Callastar Basa Bark Current	(V _{CB} = 10 V)	I _{CBO}	CNX83A.W			20	nA
Collector-Base Dark Current			SL5583.W				
Capacitance	$(V_{CE} = 0 \text{ V}, f = 1 \text{ MHz})$	C _{CE}	ALL		8		pF

Note

^{**} Typical values at T_A = 25°C



CNX82A.W, CNX83A.W, SL5582.W & SL5583.W

TRANSFER CHARACTERISTICS (T _A = 25°C Unless otherwise specified.)							
DC Characteristic	Test Conditions	Symbol	Device	Min	Typ**	Max	Units
Current Transfer Ratio, Collector-Emitter	$(I_F = 10 \text{ mA}, V_{CE} = 0.4 \text{ V})$	CTR	ALL	40			%
	$(I_F = 10 \text{ mA}, V_{CE} = 5 \text{ V})$		CNX82A.W CNX83A.W	40		250	
			SL5582.W SL5583.W	40		320	
	$(I_F = 10 \text{ mA}, V_{CE} = 5 \text{ V})$ $(T_A = 100^{\circ}\text{C})$		SL5582.W SL5583.W	25		320	
	(I _F = 1 mA, V _{CE} = 5 V)		CNX82A.W CNX83A.W	10		100	
	$(I_F = 2 \text{ mA}, V_{CE} = 5 \text{ V})$		SL5582.W SL5583.W	20			
	$(I_F = 2 \text{ mA}, V_{CE} = 5 \text{ V})$ $(T_A = 100^{\circ}\text{C})$		SL5582.W SL5583.W	15			
Saturation Voltage	$(I_F = 10 \text{ mA}, I_C = 4 \text{ mA})$	V _{CE(sat)}	ALL		0.19	0.4	V
	$(I_C = 2 \text{ mA}, V_{CC} = 5 \text{ V}, R_L = 100 \Omega)$	t _{on}	ALL		3		μs
Turn-on Time	$(I_C = 2 \text{ mA}, V_{CC} = 5 \text{ V}, R_L = 1 \text{ k}\Omega)$		ALL		12		
	$(I_F = 16 \text{ mA}, V_{CC} = 5 \text{ V}, R_L = 1 \text{ k}\Omega)$		SL5582.W SL5583.W			20	
	$(I_C = 2 \text{ mA}, V_{CC} = 5 \text{ V}, R_L = 100 \Omega)$	- t _{off}	ALL		3		
Turn off Time	$(I_C = 2 \text{ mA}, V_{CC} = 5 \text{ V}, R_L = 1 \text{ k}\Omega)$		ALL		12		
Turn-off Time	$(I_F = 16 \text{ mA}, V_{CC} = 5 \text{ V}, R_L = 1 \text{ k}\Omega)$		SL5582.W SL5583.W			50	μs

ISOLATION CHARACTERISTICS						
Characteristic	Test Conditions	Symbol	Min	Typ**	Max	Units
Input-Output Isolation Voltage	$(I_{I-O} \le 1 \mu A, 1 min.)$	V _{ISO}	5300			Vac(rms)
Isolation Resistance	$(V_{I-O} = 500 \text{ VDC})$	R _{ISO}	10 ¹¹			Ω
Isolation Capacitance	$(V_{I-O} = \emptyset, f = 1 MHz)$	C _{ISO}		0.5		pf
External air gap (clearance)			9.6			mm
External tracking path (creepage)			8.0			mm
Internal plastic gap (clearance)			1.0			mm

Note

ORDERING INFORMATION

		Order Entry Identifier	Description
3	300	.300W	VDE 0884

^{**} Typical values at $T_A = 25$ °C



CNX82A.W, CNX83A.W, SL5582.W & SL5583.W

TYPICAL CHARACTERISTICS

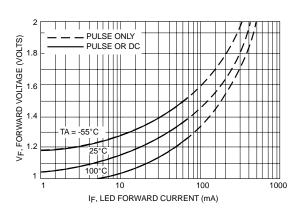


Figure 1. LED Forward Voltage versus Forward Current

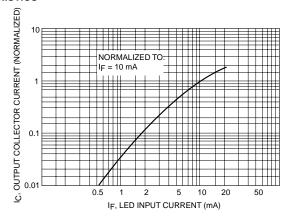


Figure 2. Output Current versus Input Current

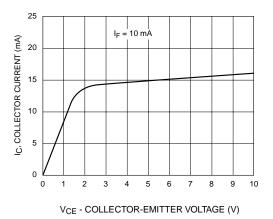


Figure 3. Collector Current versus Collector-Emitter Voltage

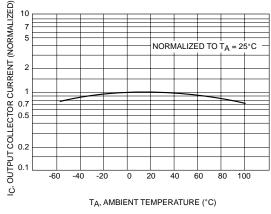


Figure 4. Output Current versus Ambient Temperature

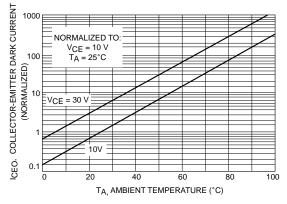


Figure 5. Dark Current versus Ambient Temperature

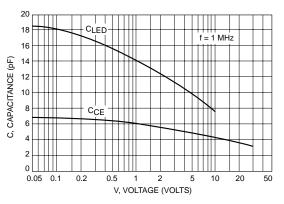


Figure 6. Capacitance versus Voltage



SUPER BRIGHT PLCC-2 PACKAGE SURFACE MOUNT LED LAMP SURFACE MOUNT LED LAMP

DISCLAIMER

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS.

LIFE SUPPORT POLICY

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF THE PRESIDENT OF FAIRCHILD SEMICONDUCTOR CORPORATION. As used herein:

- Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury of the user.
- 2. A critical component in any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

www.fairchildsemi.com

© 2000 Fairchild Semiconductor Corporation

4 of 4 12/6/00 300089B

This datasheet has been download from:

www.datasheetcatalog.com

Datasheets for electronics components.